

N-Channel 20V (D-S) MOSFET

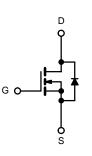
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
20	0.012 at V _{GS} = 10 V	12	6.1 nC			
	0.015 at V _{GS} = 4.5 V	11	0.1110			

FEATURES

- Halogen-free
- TrenchFET[®] Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

Notebook CPU Core
 High-Side Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	S T _A = 25 °C, unles	s otherwise not	ted		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	20	V		
Gate-Source Voltage		V _{GS}			± 16
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	I _D	12 11 10 ^{b, c} 8 ^{b, c}		
Pulsed Drain Current		I _{DM}	47	— A	
Continuous Source-Drain Diode Current	e Current $\frac{T_{C} = 25 \text{ °C}}{T_{A} = 25 \text{ °C}}$		3.7 2.0 ^{b, c}	-	
Single Pulse Avalanche Current	1 0.1 ml l	I _{AS}	20		
alanche Energy L = 0.1 mH		E _{AS}	21	mJ	
Maximum Power Dissipation	$T_{C} = 25 \text{ °C}$ $T_{C} = 70 \text{ °C}$ $T_{A} = 25 \text{ °C}$ $T_{A} = 70 \text{ °C}$	P _D	4.1 2.5 2.2 ^{b, c} 1.3 ^{b, c}	W	
Operating Junction and Storage Temperature Ra	T _J , T _{stq}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	39	55	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	25	29	0/11	

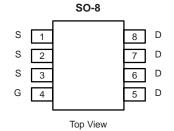
Notes:

a. Base on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 85 °C/W.





SPECIFICATIONS $T_J = 25 \text{ °C}$		erwise noted				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				-		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	20			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		26		- mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	1 <u>0</u> – 200 μ. (- 6		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V$, $V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current	lana	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate voltage Drain Current	IDSS	$V_{DS}\!=\!\!20V$, $V_{GS}\!=$ 0 V, $T_{J}\!=$ 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			А
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	0.012			Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}			0.015		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 10 A		50		S
Dynamic ^b						
Input Capacitance	C _{iss}			800		pF
Output Capacitance	C _{oss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		165		
Reverse Transfer Capacitance	C _{rss}			73		
		$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		15	23	
Total Gate Charge	Qg			6.8	10.2	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		
Gate-Drain Charge	Q _{gd}			2.3		
Gate Resistance	R _g	f = 1 MHz	0.36	1.8	3.6	Ω
Turn-On Delay Time	t _{d(on)}			16	23	
Rise Time	t _r	V_{DD} = 10 V, R _I = 1.4 Ω		12	16	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t _f	-		10	18	
Turn-On Delay Time	t _{d(on)}			8	16	ns
Rise Time	t _r	$V_{DD} = 10 \text{ V}, \text{ R}_{1} = 1.4 \Omega$		10	20	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		16	22	
Fall Time	t _f	-		8	15	
Drain-Source Body Diode Characteris				1	1	1
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			10	
Pulse Diode Forward Current ^a	I _{SM}				50	A
Body Diode Voltage	V _{SD}	I _S = 9 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	-		15	30	ns
Body Diode Reverse Recovery Charge	Q _{rr}			6	12	nC
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 \text{ °C}$		8		_
Reverse Recovery Rise Time	t _b			7		ns
Notes:	b			· ·	1	1

emi

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



3.0

 $T_{\rm C} = -55$

C

18

24

V_{GS} = 4.5 V

100

125

150

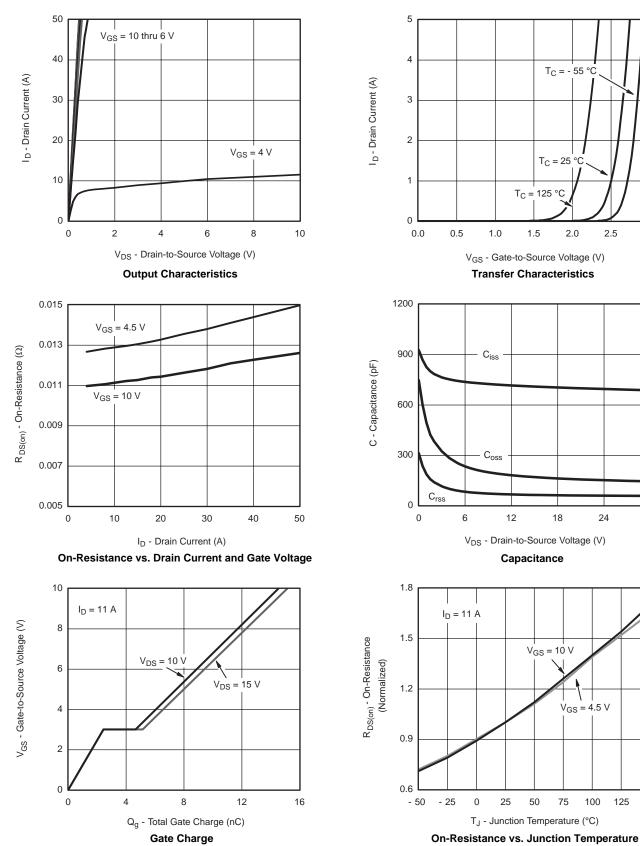
75

30

2.0

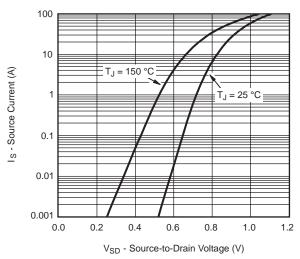
2.5

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

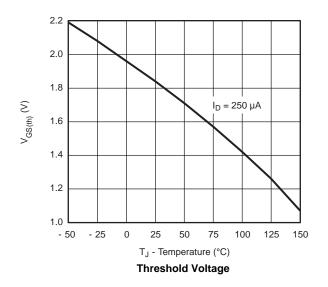


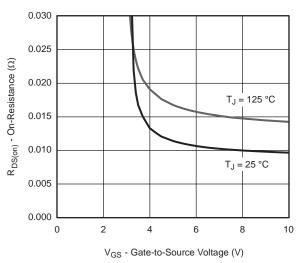


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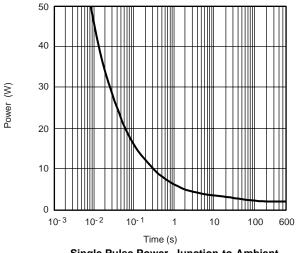




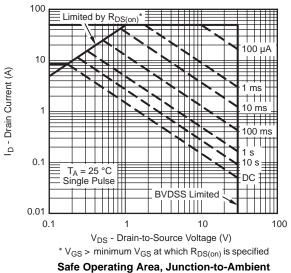




On-Resistance vs. Gate-to-Source Voltage

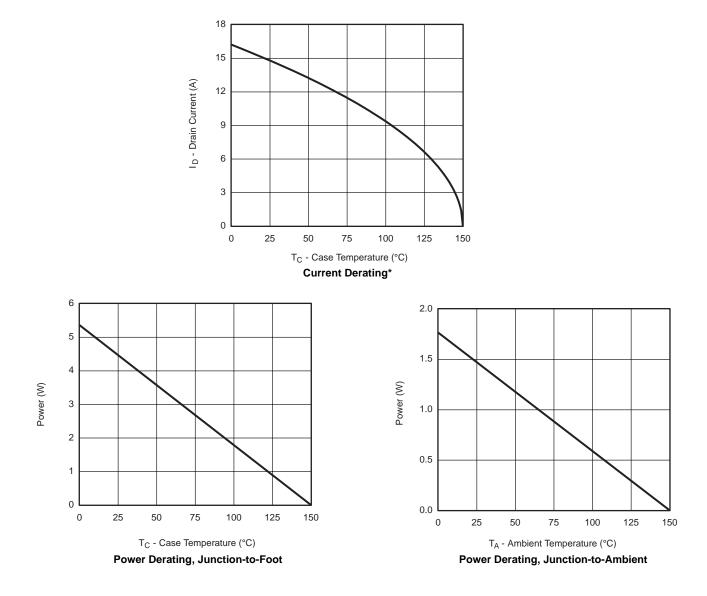


Single Pulse Power, Junction-to-Ambient



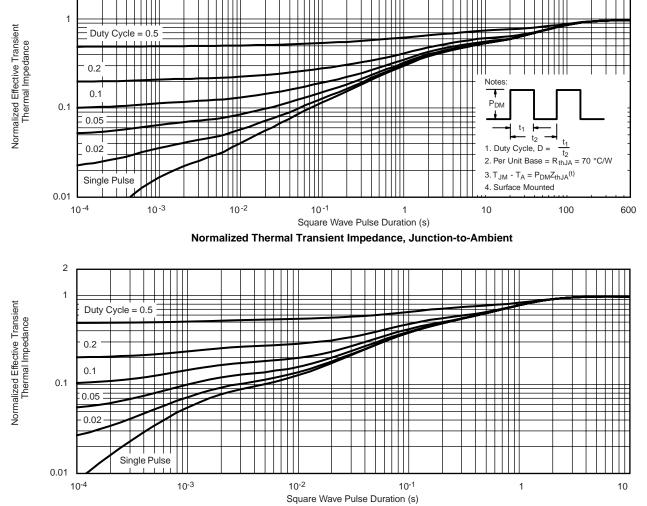


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

2



Bsemi

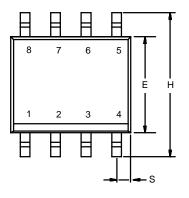
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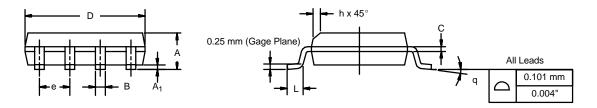
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD

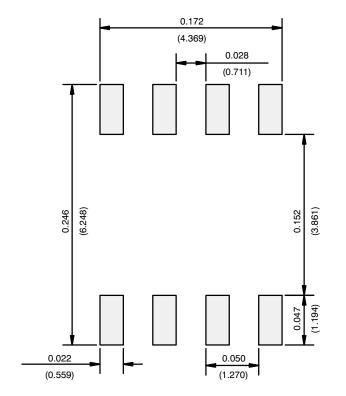




	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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